



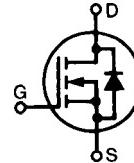
High Voltage Power MOSFETs

N-Channel Enhancement Mode
Avalanche Rated, High dv/dt

Preliminary Data Sheet

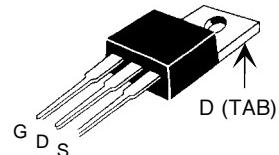
IXTA/IXTP 3N120
IXTA/IXTP 3N110

V_{DSS}	I_{D25}	R_{DS(on)}
1200 V	3 A	4.5 Ω
1100 V	3 A	4.0 Ω

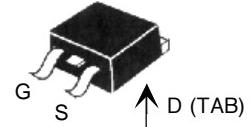


Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	T _J = 25°C to 150°C	3N120	1200	V
		3N110	1100	V
V_{DGR}	T _J = 25°C to 150°C; R _{GS} = 1 MΩ	3N120	1200	V
		3N110	1100	V
V_{GS}	Continuous		±20	V
V_{GSM}	Transient		±30	V
I_{D25}	T _C = 25°C		3	A
I_{DM}	T _C = 25°C, pulse width limited by T _{JM}		12	A
I_{AR}	T _C = 25°C		3	A
E_{AR}	T _C = 25°C		20	mJ
E_{AS}			700	mJ
dv/dt	I _S ≤ I _{DM} , di/dt ≤ 100 A/μs, V _{DD} ≤ V _{DSS} , T _J ≤ 150°C, R _G = 2 Ω		5	V/ns
P_D	T _C = 25°C		150	W
T_J		-55 to +150		°C
T_{JM}		150		°C
T_{stg}		-55 to +150		°C
T_L	1.6 mm (0.063 in) from case for 10 s		300	°C
M_d	Mounting torque (TO-220)		1.13/10	Nm/lb.in.
Weight	TO-220		4	g
	TO-263		2	g

TO-220 (IXTP)



TO-263 (IXTA)



G = Gate D = Drain
S = Source TAB = Drain

Features

- International standard packages
- Low R_{DS(on)}
- Rated for unclamped Inductive load Switching (UIS)
- Molding epoxies meet UL 94 V-0 flammability classification

Advantages

- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values		
		(T _J = 25°C, unless otherwise specified)	min.	typ.
V_{DSS}	V _{GS} = 0 V, I _D = 1 mA	3N120	1200	V
		3N110	1100	V
V_{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA		2.5	4.5 V
I_{GSS}	V _{GS} = ±20 V _{DC} , V _{DS} = 0			±100 nA
I_{DSS}	V _{DS} = 0.8 V _{DSS} V _{GS} = 0 V	T _J = 25°C T _J = 125°C		25 μA 1 mA
R_{DS(on)}	V _{GS} = 10 V, I _D = 0.5 I _{D25} Note 1	3N120 3N110		4.5 Ω 4.0 Ω

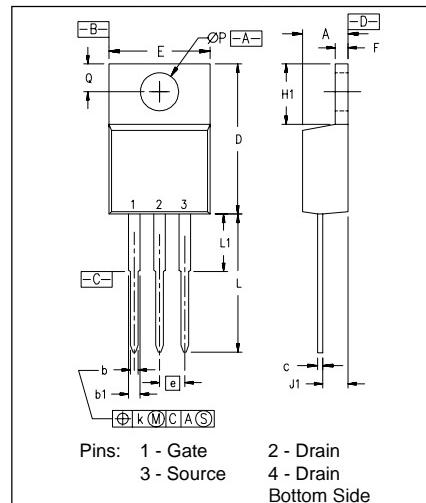
Symbol	Test Conditions	Characteristic Values			
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.	max.
g_{fs}	$V_{DS} = 10 \text{ V}; I_D = 0.5 \cdot I_{D25}$, Note 1	1.5	2.2	S	
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	1050	1300	pF	
		100	125	pF	
		25	50	pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$ $R_G = 4.7 \Omega$ (External),	17		ns	
		15		ns	
		32		ns	
		18		ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$	39		nC	
		9		nC	
		22		nC	
R_{thJC}			0.8	K/W	
R_{thCK}	(TO-220)	0.25		K/W	

Source-Drain Diode

Characteristic Values
($T_J = 25^\circ\text{C}$, unless otherwise specified)

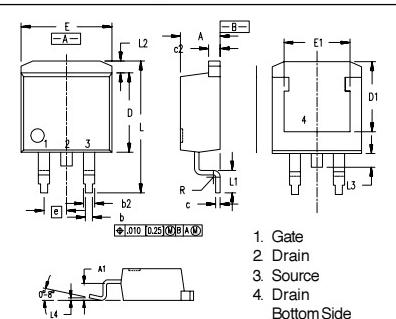
Symbol	Test Conditions	min.	typ.	max.
I_s	$V_{GS} = 0 \text{ V}$		3	A
I_{SM}	Repetitive; pulse width limited by T_{JM}		12	A
V_{SD}	$I_F = I_S, V_{GS} = 0 \text{ V}$, Note 1		1.5	V
t_{rr}	$I_F = I_S, -di/dt = 100 \text{ A}/\mu\text{s}, V_R = 100 \text{ V}$	700		ns

Notes: 1. Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$

TO-220 (IXTP) Outline


SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.170	.190	4.32	4.83
b	.025	.040	0.64	1.02
b1	.045	.065	1.15	1.65
c	.014	.022	0.35	0.56
D	.580	.630	14.73	16.00
E	.390	.420	9.91	10.66
e	.100	BSC	2.54	BSC
F	.045	.055	1.14	1.40
H1	.230	.270	5.85	6.85
J1	.090	.110	2.29	2.79
k	0	.015	0	0.38
L	.500	.550	12.70	13.97
L1	.110	.230	2.79	5.84
ØP	.139	.161	3.53	4.08
Q	.100	.125	2.54	3.18

NOTE: This drawing will meet all dimensions requirement of JEDEC outline TO-220 AB.

TO-263 (IXTA) Outline


Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	4.06	4.83	.160	.190
A1	2.03	2.79	.080	.110
b	0.51	0.99	.020	.039
b2	1.14	1.40	.045	.055
c	0.46	0.74	.018	.029
c2	1.14	1.40	.045	.055
D	8.64	9.65	.340	.380
D1	7.11	8.13	.280	.320
E	9.65	10.29	.380	.405
E1	6.86	8.13	.270	.320
e	2.54	BSC	.100	BSC
L	14.61	15.88	.575	.625
L1	2.29	2.79	.090	.110
L2	1.02	1.40	.040	.055
L3	1.27	1.78	.050	.070
L4	0	0.38	0	.015
R	0.46	0.74	.018	.029

IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,881,106
4,850,072 4,931,844

5,017,508 5,049,961 5,187,117 5,486,715
5,034,796 5,063,307 5,237,481 5,381,025

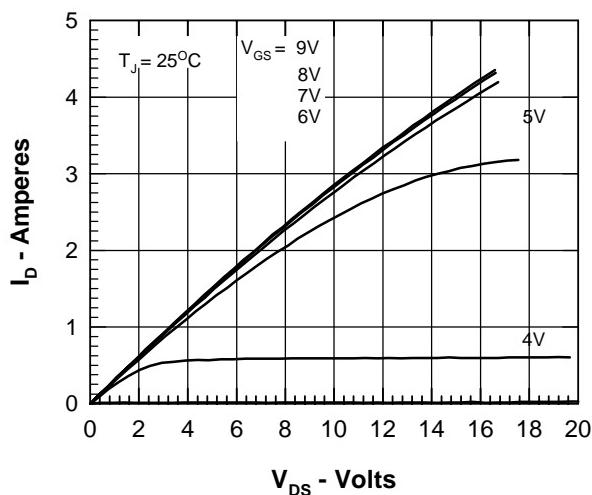


Fig. 1 Output Characteristics @ $T_J = 25^\circ\text{C}$

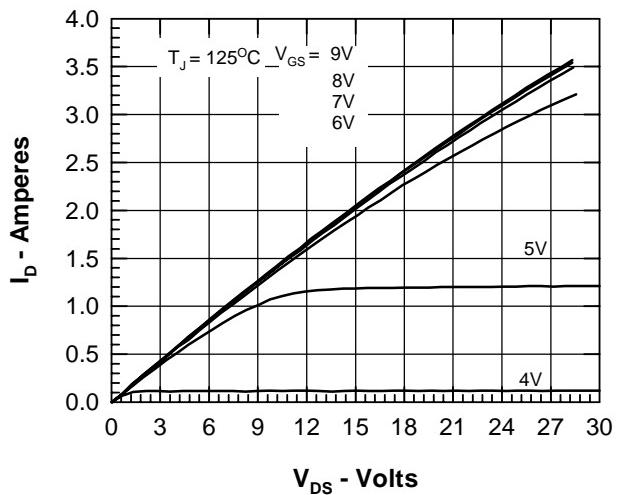


Fig. 2 Output Characteristics @ $T_J = 125^\circ\text{C}$

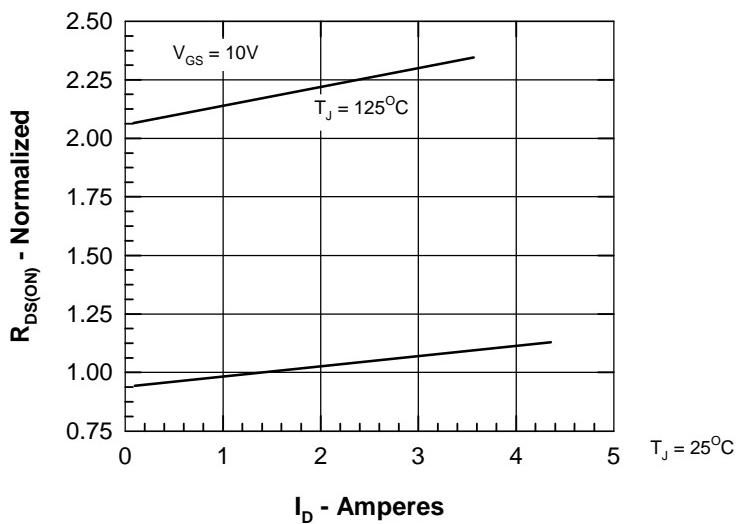


Fig. 3 $R_{DS(\text{ON})}$ vs. Drain Current

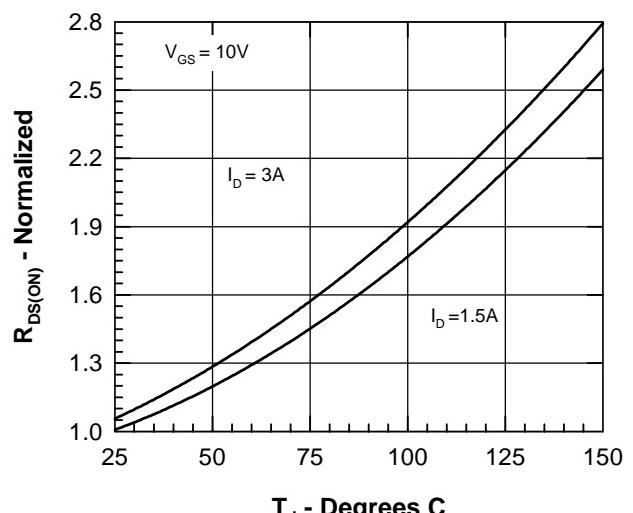


Fig. 4 Temperature Dependence of Drain to Source Resistance

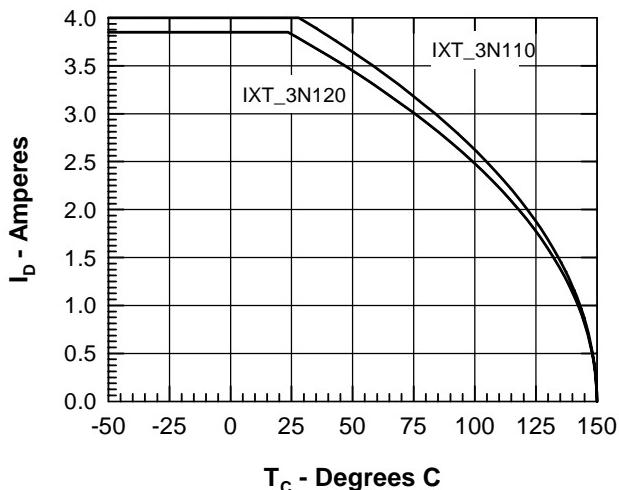


Fig. 5 Drain Current vs. Case Temperature

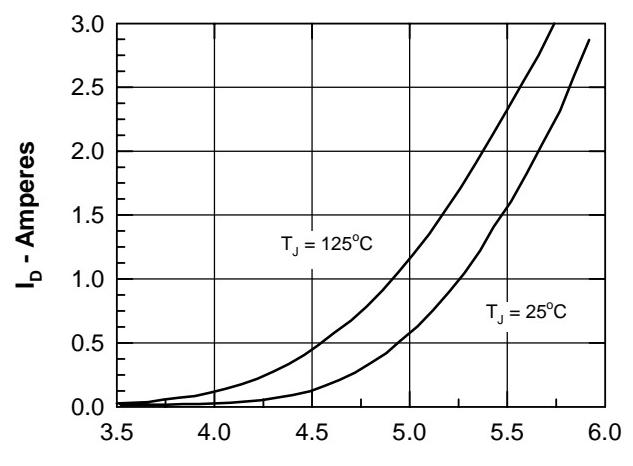


Fig. 6 Drain Current vs Gate Source Voltage

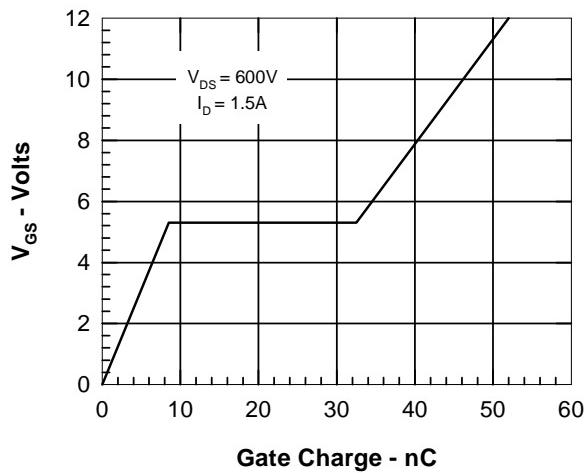


Fig. 7 Gate Charge Characteristic Curve

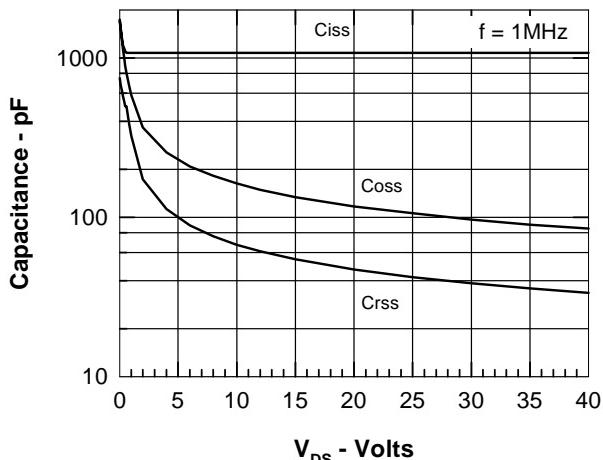


Fig. 8 Capacitance Curves

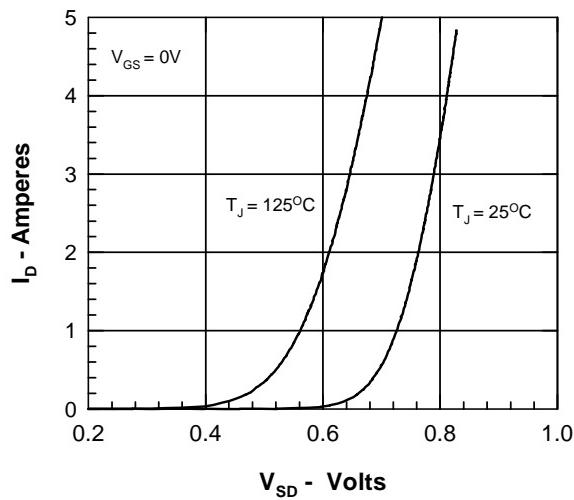


Fig. 9 Drain Current vs Drain to Source Voltage

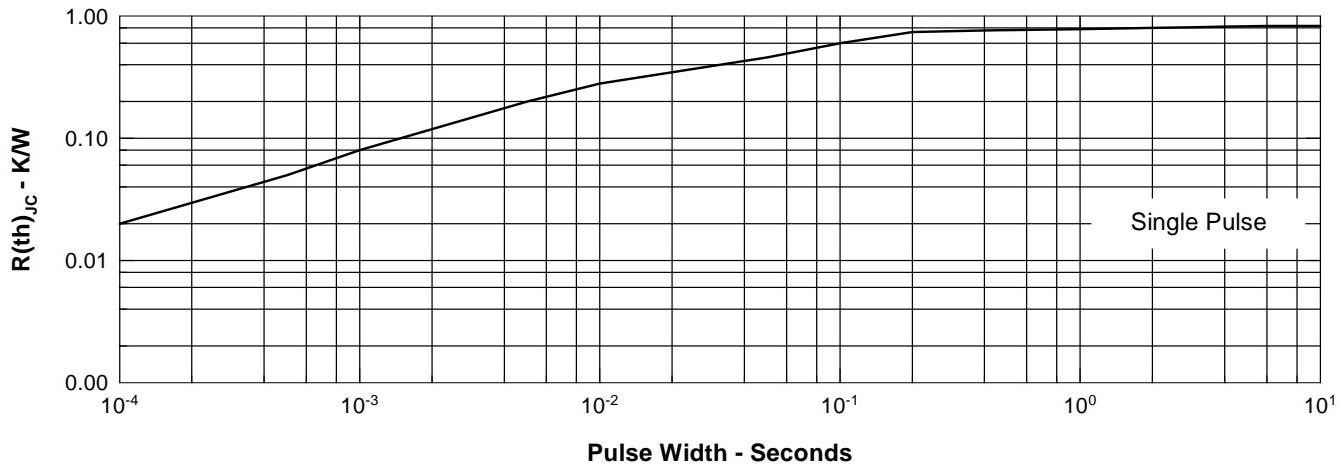


Fig. 10 Transient Thermal Impedance

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